

## RELIABILITY DATA

**LTC1693**

**10/26/2003**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF <sup>(2)</sup> FAILURES
SOIC/SOT/MSOP	280 280	9813	0310	240.11 240.11	0 0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	350 350	9816	0309	14.40 14.40	0 0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,347 2,347	0014	0309	234.70 234.70	0 0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	150 150	0102	0309	15.00 15.00	0 0

(1) Assumes Activation Energy = 0.7 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 49.29 FITS

(3) Mean Time Between Failures in Years = 2,314

Note: 1 FIT = 1 Failure in One Billion Hours.